

ABSTRACT OF THE DISCLOSURE

A failure data logging circuit for logging not only necessary failure log data but also effective data including a number of failures counted on data not stored in a failure analysis memory, for the failure analysis of devices, in the failure analysis memory. The failure log data logging circuit (1) for logging failure log data of a device under test based on a plurality of test patterns in a failure analysis memory when a IC tester tests the device, comprises: a counter (3) for counting a number of failures of I/O (PASS/FAIL) data outputted from an output line of I/O (PASS/FAIL) data of the device under test; and a masking circuit (4) for masking I/O (PASS/FAIL) data outputted after the number of failures counted by the counter becomes equal to a predetermined value.

This Sheet Has Been Replaced

